Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/774,883	FUNG ET AL.	
Examiner	Art Unit	
Phallaka Kik	2825	

	SEARCHED		
Class	Subclass	Date	Examiner
716	6,9,10,16, 18	2/3/2006	PK
716	16,18	2/7/2006	PK
Above	updated	5/27/2006	PK
Above	updated	8/21/2006	PK
			" -

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
716	6,9,10,16	8/21/2006	PK		
716	18	8/21/2006	PK		
USPGPUB (See attached)		8/21/2006	PK		

SEARCH NO (INCLUDING SEARCI		)
	DATE	EXMR
BRS (EAST)USPAT, USPGPUB Class/sub searched: 716/1-18 (see attached)	2/3/2006	PK
Above updated (see attached)	5/27/2006	РК
Above updated (see attached)	8/21/2006	PK
BRS (EAST)USPAT, USPGPUB Class/Sub searched: 16,18	2/7/2006	PK
EPO, JPO, IBM TDB, Derwent (see attached)	2/3/2006	PK
IEE/IEEE XPlore (see attached)	2/3/2006	PK